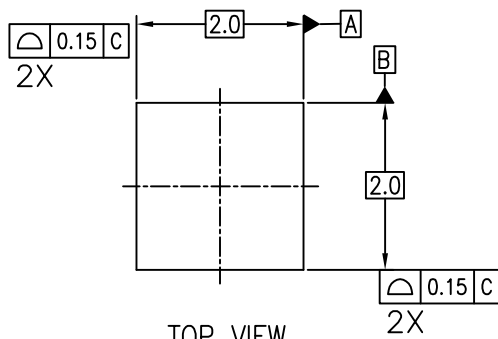
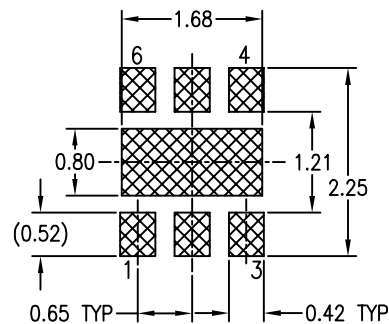


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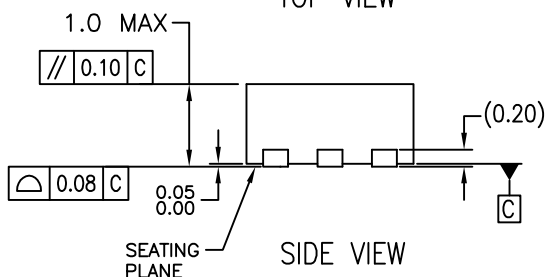
REVISIONS			
LTR	DESCRIPTION	EDCN	DATE
A	RELEASE TO DOCUMENT CONTROL		2-7-2002
			FEITAN



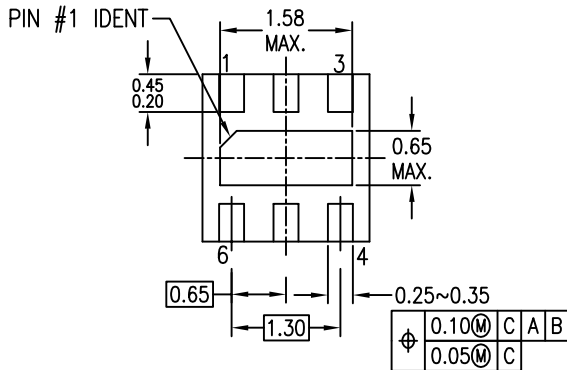
TOP VIEW



RECOMMENDED LAND PATTERN



SIDE VIEW



BOTTOM VIEW

NOTES:

- A. CONFORMS TO JEDEC REGISTRATION MO-229, VARIATION VCCC, DATED 11/2001
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994

MLP06BrevA

APPROVALS	DATE	Bayan Lepas, FIZ, SEMICONDUCTOR 11900, Penang, Malaysia.	6LD,MLP DUAL,JEDEC MO-229, 2MM SQUARE		
DRAWN FEITAN	27-6-2002		SCALE N/A	SIZE N/A	DRAWING NUMBER MKT-MLP06B
DFTG. CHK.			REV A		
ENGR. CHK.			DO NOT SCALE DRAWING		
PROJECTION INCH EMMJ		SHEET 1 of 1			